

Photo Modules for PCM Remote Control Systems

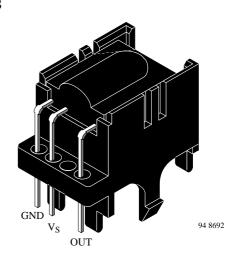
Available types for different carrier frequencies

Type	f_0	Type	f_0
TSOP1130TB1	30 kHz	TSOP1133TB1	33 kHz
TSOP1136TB1	36 kHz	TSOP1137TB1	36.7 kHz
TSOP1138TB1	38 kHz	TSOP1140TB1	40 kHz
TSOP1156TB1	56 kHz		

Description

The TSOP11..TB1 – series are miniaturized receivers for infrared remote control systems. PIN diode and preamplifier are assembled on lead frame, the epoxy package is designed as IR filter. The demodulated output signal can directly be decoded by a microprocessor.

The main benefit is the operation with short burst transmission codes (e.g. RECS 80) and high data rates.



Features

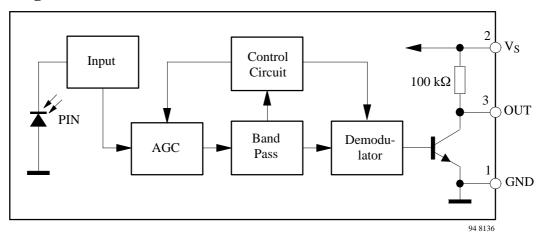
- Photo detector and preamplifier in one package
- Internal filter for PCM frequency
- Improved shielding against electrical field disturbance

Special Features

- Enhanced data rate of 2400 bit/s
- Operation with short bursts possible (≥6 cycles/burst)

- TTL and CMOS compatibility
- Output active low
- Low power consumption
- High immunity against ambient light

Block Diagram





Absolute Maximum Ratings

 $T_{amb}=25\,^{\circ}C$

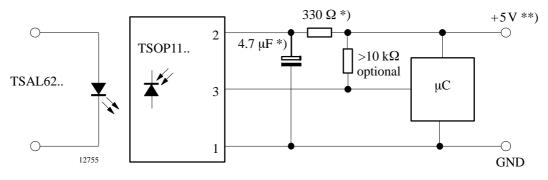
Parameter	Test Conditions	Symbol	Value	Unit
Supply Voltage	(Pin 2)	V_{S}	-0.36.0	V
Supply Current	(Pin 2)	I_S	I_{S} 5	
Output Voltage	(Pin 3)	V_{O}	-0.36.0	V
Output Current	(Pin 3)	I _O	5	mA
Junction Temperature		T_j	100	°C
Storage Temperature Range		T_{stg}	-25+85	°C
Operating Temperature Range		T _{amb}	-25+85	°C
Power Consumption	$(T_{amb} \le 85 \degree C)$	P _{tot}	50	mW
Soldering Temperature	$t \le 5 s$	T_{sd}	260	°C

Basic Characteristics

 $T_{amb} = 25\,^{\circ}C$

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
Supply Current (Pin 2)	$V_S = 5 \text{ V}, E_v = 0$	I_{SD}	0.4	0.5	0.8	mA
	$V_S = 5 \text{ V}, E_v = 40 \text{ klx}, \text{ sunlight}$	I _{SH}		1		mA
Transmission Distance	$E_v = 0$, test signal see fig.8, IR diode TSIP5201, $I_F = 0.4$ A	d		35		m
Output Voltage Low (Pin 3)	$I_{OSL} = 0.5 \text{ mA}, E_e = 0.7 \text{ mW/m}^2,$ f = f _o , test signal see fig.7	V _{OSL}			250	mV
Irradiance (30 – 40 kHz)	Test signal see fig.7	E _{e min}		0.4	0.6	mW/m^2
	Test signal see fig.8	E _{e min}		0.35	0.5	mW/m^2
Irradiance (56 kHz)	Test signal see fig.7	E _{e min}		0.45	0.7	mW/m^2
	Test signal see fig.8	E _{e min}		0.40	0.6	mW/m^2
Irradiance	Test signal see fig.7	E _{e max}	30			W/m ²
Directivity	Angle of half transmission distance	φ1/2		±45		deg

Application Circuit



*) only necessary to suppress power supply disturbances

^{**)} tolerated supply voltage range : $4.5\,\mathrm{V}{<}\mathrm{V_S}{<}5.5\,\mathrm{V}$

Typical Characteristics $(T_{amb} = 25^{\circ}C \text{ unless otherwise specified})$

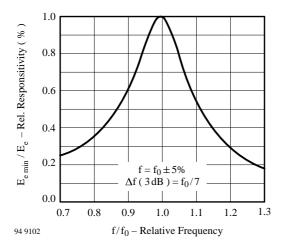


Figure 1. Frequency Dependence of Responsivity

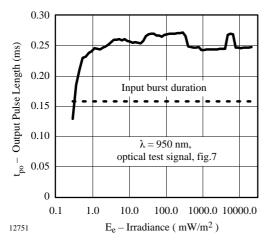


Figure 2. Pulse Length and Sensitivity in Dark Ambient

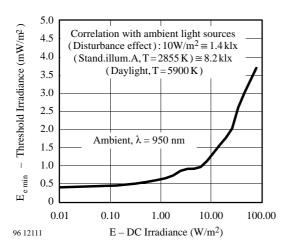


Figure 3. Sensitivity in Bright Ambient

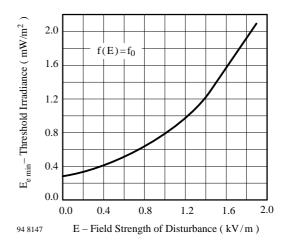


Figure 4. Sensitivity vs. Electric Field Disturbances

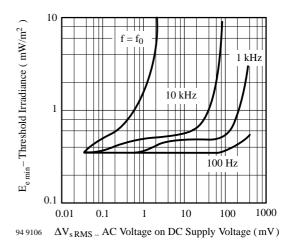


Figure 5. Sensitivity vs. Supply Voltage Disturbances

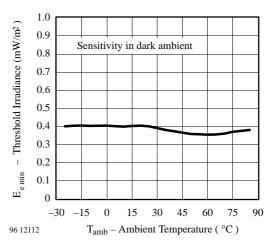
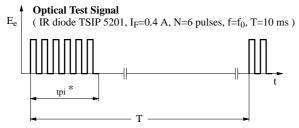


Figure 6. Sensitivity vs. Ambient Temperature





* $t_{pi} \ge 6/fo$ is recommended for optimal function

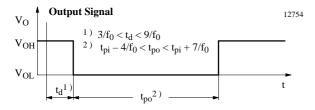
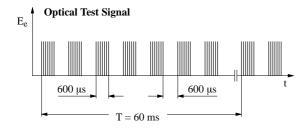


Figure 7. Output Function



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V_O Output Signal, (see Fig.10)
V_{OH} V_{OL} T_{on} t

Figure 8. Output Function

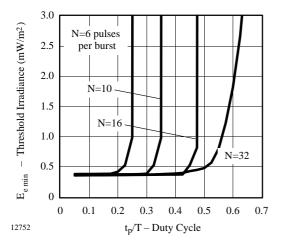


Figure 9. Sensitivity vs. Duty Cycle

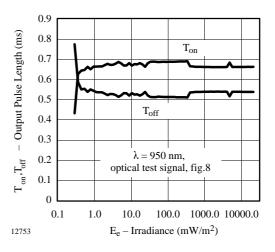


Figure 10. Output Pulse Diagram

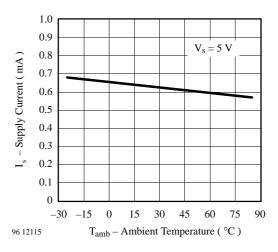


Figure 11. Supply Current vs. Ambient Temperature

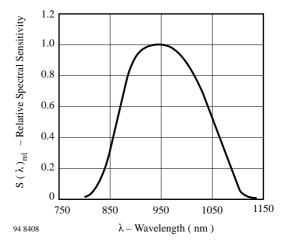
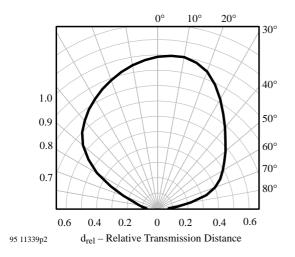


Figure 12. Relative Spectral Sensitivity vs. Wavelength







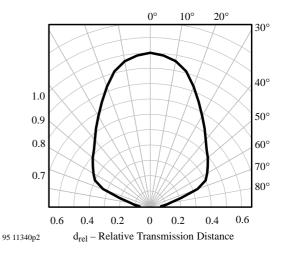
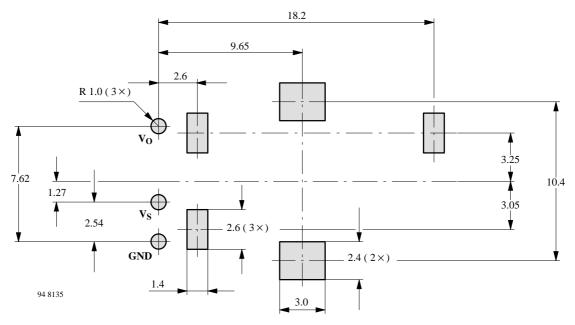


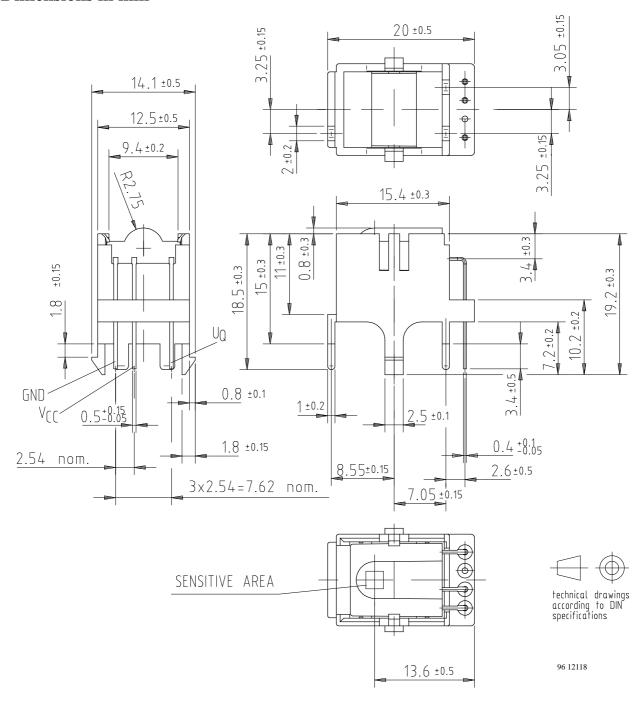
Figure 14. Horizontal Directivity ϕ_X

Board Hole Diagram (Solder side, dimensions in mm, tolerances ± 0.3 mm)





Dimensions in mm





Ozone Depleting Substances Policy Statement

It is the policy of **TEMIC TELEFUNKEN microelectronic GmbH** to

- 1. Meet all present and future national and international statutory requirements.
- 2. Regularly and continuously improve the performance of our products, processes, distribution and operating systems with respect to their impact on the health and safety of our employees and the public, as well as their impact on the environment.

It is particular concern to control or eliminate releases of those substances into the atmosphere which are known as ozone depleting substances (ODSs).

The Montreal Protocol (1987) and its London Amendments (1990) intend to severely restrict the use of ODSs and forbid their use within the next ten years. Various national and international initiatives are pressing for an earlier ban on these substances.

TEMIC TELEFUNKEN microelectronic GmbH semiconductor division has been able to use its policy of continuous improvements to eliminate the use of ODSs listed in the following documents.

- 1. Annex A, B and list of transitional substances of the Montreal Protocol and the London Amendments respectively
- 2. Class I and II ozone depleting substances in the Clean Air Act Amendments of 1990 by the Environmental Protection Agency (EPA) in the USA
- 3. Council Decision 88/540/EEC and 91/690/EEC Annex A, B and C (transitional substances) respectively.

TEMIC can certify that our semiconductors are not manufactured with ozone depleting substances and do not contain such substances.

We reserve the right to make changes to improve technical design and may do so without further notice.

Parameters can vary in different applications. All operating parameters must be validated for each customer application by the customer. Should the buyer use TEMIC products for any unintended or unauthorized application, the buyer shall indemnify TEMIC against all claims, costs, damages, and expenses, arising out of, directly or indirectly, any claim of personal damage, injury or death associated with such unintended or unauthorized use.

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